

Laboratori Nazionali di Legnaro (Istituto Nazionale di Fisica Nucleare) Observation of beamlet displacement and parallelism in NIO1 **CONSORZIO RFX**

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¹⁾ INFN-LNL, viale dell'Università 2, 35020 Legnaro (PD), Italy; ²⁾ Consorzio RFX (CNR,ENEA,INFN,UNIPD,Acciaierie Venete SpA) Corso Stati Uniti 4, 35127 Padova, Italy Abstract: The compact radiofrequency negative ion source NIO1 (Negative Ion Optimization phase 1) has many available CF40 ports for side views of beamlet matrix. Two kinds of deflecting magnetic systems are present, namely the fringe field of the source filter Bs (mostly directed in x direction where z is beam extraction direction) and the electron deflection filter B^d (due to magnets inserted in the extraction grid EG and the post-acceleration grid PA) mostly directed in the y direction. Their effect can be separated by cameras looking from different directions, namely CAM1 (looking from –x axis) is sensitive to B^s while CAM2 (looking from –y axis) verifies B^d effect; both cameras are also sensitive to beam optics, dependent on extracted beamlet currents, their uniformity and applied voltage. Optional algorithms for noise rejection and pre-smoothing can improve automatic recognizing of beamlet peaks, while a good fraction of images can be simply fitted by Gaussian shapes. This analysis allows to estimate beamlet displacement and deflection. Typical shapes of extracted beamlets are listed, noting in CAM2 the effect of B^d_v sign reversal (due to EG magnets) and of the compensation techniques used to obtain beamlet parallelism (in good matching); systematic analysis of correlation between images, other source measurements and simple beam simulation is also attempted. Alignment and scaling of images is discussed also with reference to background objects. Moreover, beamlet convergence was sometimes observed, and corresponding datasets were tagged for optics correction. Finally beam size information useful for Faraday cup design is obtained.

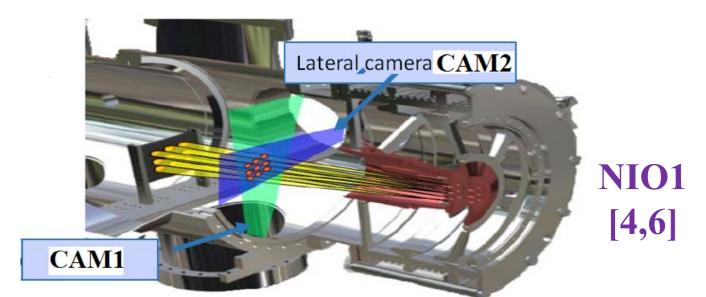
I. INTRODUCTION and SETUP

An ideal tool to optimize the extraction for a H- ion source would allow to map the beam current density. An approximation to these tool does exist, consisting in vibible light [7] observing the Balmer line camera emission following collision of ions and residual gas. Relevant processes [1, 2] are

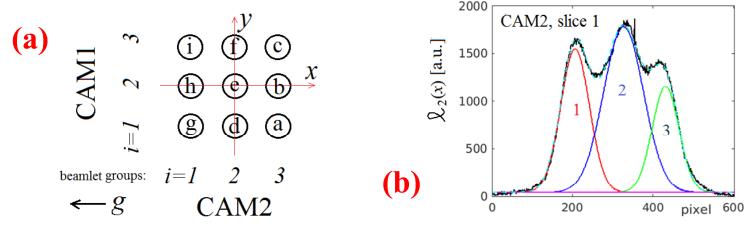
> $H^{-}(\text{fast}) + H_2 \longrightarrow H^{-}(\text{fast}) + H^* + H^*$ $H^{-}(\text{fast}) + H_2 \longrightarrow H^{*}(\text{fast}) + H_2 + e$ $H^*(n=3) \longrightarrow H^*(n=2) + \gamma(656.28nm)$

Assuming rapid decay, light emission density is L(x, y, z) about proportional to $|\mathbf{j}_H^-(\mathbf{x})|$

Since z is the beam axis, method is sensitive to j_z II.a SETUP

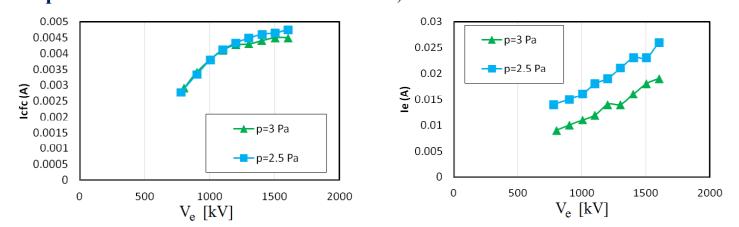


NIO1 (Negative Ion Optimization phase 1) is a H- ion source, producing 9 beamlets. The camera CAM1 and CAM2 must be placed so to avoid: direct view of the plasma; view of brighter reflections. Data can improved by: selecting adequate camera gains; considering as 'data region' only the image portions free from reflections; covering some walls by a black foil.



(a) Scheme of beamlet matrix, CAM1 and CAM2, and their projections, which superpose the 9 beamlets in groups, 1, 2,3 (of course beamlet groups of CAM1 differs from CAM2 ones); (b) fitting peak of CAM1 profiles; with the ambitious purpose of inferring the current contents of beamlet groups. **II.b** Typical total currents

In 2019 (Cs-free regime), where most of this poster analysis originates, current was estimated to reach 8-11 mA; with Cs results more than doubled at similar conditions. Here we limited to cases with lower current and better optics, for example the 2019 results have 4 mA current: for some 2022 results see below



Since x,y ion positions are near z-axis, in 1st approximation we can use a simple light collection model for CAM1 and CAM2

 $\ell_1(z, y) = g_1$ $\ell_2(z,x) = g_2 \int dz$

which relat

III.b Primary fits Since H⁻ scattering is possible and extraction is complicate, a 3 peak gaussian model was initially tried (+a 4th peak for background)

 $\bar{\ell}_1(z_k)$

N = 3 (with label 'fit 3g' so a polynomial background is often added

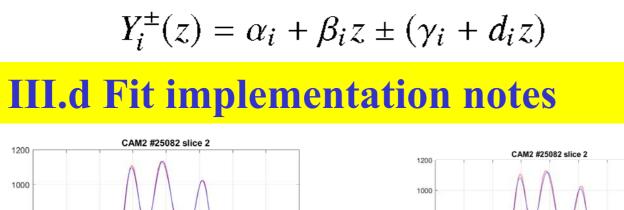
 $\bar{\ell}_1(z_k, y) \cong A$

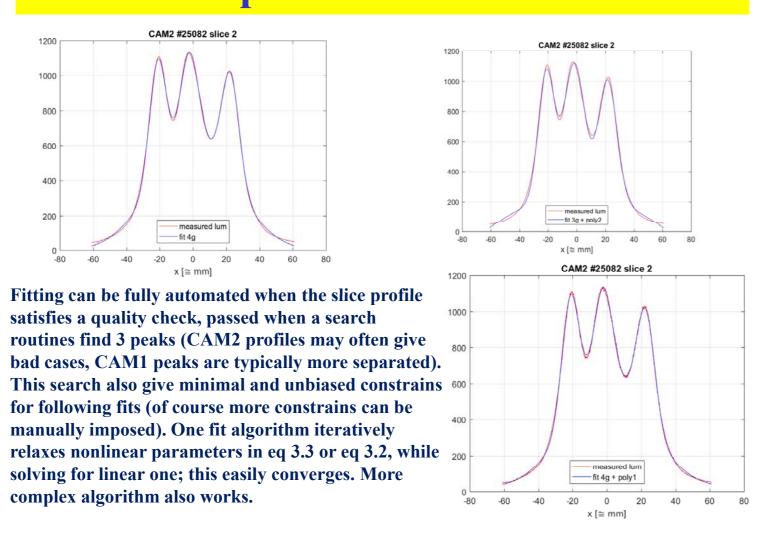
For N = 4, we must set C = 0 (with the label 'fit 4g + 1p') N = 3 we consider (label 'fit 3g + 2p') the Cy^2 term or exclude it ('fit 3g + 1p')

III.c Secondary fits

results of the eq. (3.3) fit

For any b.group we can define the lower and upper border $Y^{\pm}(z)$





complex algorithm also works.

The 'fit 4g' tends to underestimate tails; the fit 3g+2p tends to overestimate them (see figure above); fit 4g+1p gives typically small errors (compliant with naive error estimate of 10 counts), as in the case shown here above. Anyway, a final choice among these fits is pending and it depends also physical adequacy of results, shown later. In general these fits well perform in typical cases

III MODEL FOR FITS

$$dx \ L(x, y, z) \propto \int dx \ j_z(x, y, z) \equiv I_1(z, y)$$

$$dy \ L(x, y, z) \propto \int dy \ j_z(x, y, z) \equiv I_2(z, x)$$
(3.1)
tes the gains as $g_2 \int dy \ \ell_1 = g_1 \int dx \ \ell_2$

 $\bar{\ell}_1(z_k, y)$ indicates average on ±5 pixels, excluding broken pixels.

$$(x, y) \cong \sum_{i=1}^{N} a_i \exp\left(-\frac{(y-b_i)^2}{2\sigma_i^2}\right)$$
 (3.2)
ith label 'fit 3g'

N = 4 (with label 'fit 4g' in following pictures) **Background light may include non-gaussian terms,**

+
$$By + Cy^2 + \sum_{i=1}^{N} a_i \exp\left(-\frac{(y-b_i)}{2\sigma_i^2}\right)$$
 (3.3)

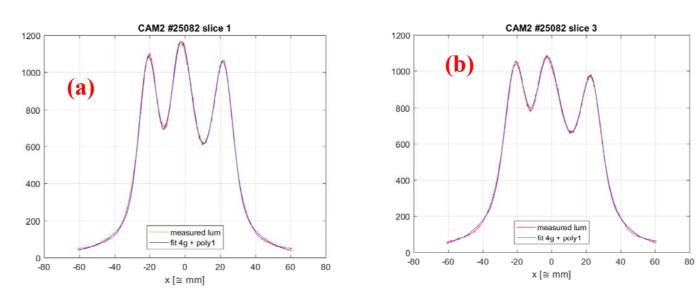
We expect that b_i (the fitted barycenter of the *i*-th beamlet group) depends linearly on z_k So we can consider a linear fit of the z-dependence of the

 $b_i(z_k) = \alpha_i + \beta_i z_k$, $\sigma_i(z_k) = \gamma_i + d_i z_k$ (3.4) the fit parameters are α_i , β_i , γ_i and the rms divergence d_i

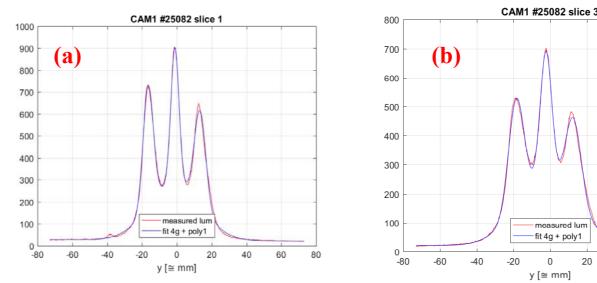
(3.5)

IV. RESULTS

To perform secondary fit eq. (3.4) we of course need that all slice profiles can be fitted: here an example:



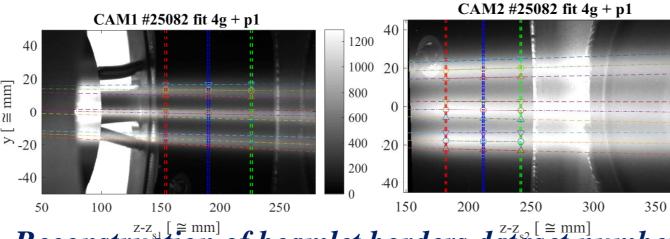
Fitting CAM2 data slices with fit '4g + 1p':(a) slice 1; (b) slice 3.



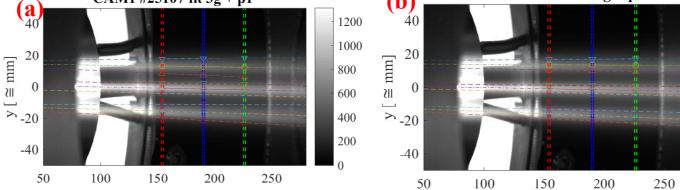
Fitting CAM1 data slices with fit '4g + 1p':(a) slice 1; (b) slice 3

IV.b Result the secondary fits

From secondary fits the rms beam divergence d_i can be calculated for each beamlet group; as well as the beam deflection β_i . A nice graphics of them is the border reconstruction



Reconstruction of beamlet borders dataset number 25082 case: CAM1 view and CAM2 view For same dataset the fit kind '3g+1p' the reconstructed border of the b. group 1 appears to miss the visible image of the 1st b. group (see below); on the contrary the fit '4g+1p' follows image more closely (tentative explanation: fit 4g+1p is more flexible in following profiles. A complete study is under progress) CAM1 #25107 fit 4g + p1 CAM1 #25107 fit 3g + p1



Reconstruction of beamlet borders for CAM1 #25107st **using two** primary fits: (a) '3g + 1p'; (b) '4g + 1p' (see definition in eq. 3.3) **IV.c** Alternative fits

2D fitting models (where the zy surface is used instead of y profile) may offer a valuable and elegant solution to border fits, but with a much greater computational cost; their study is in progress.

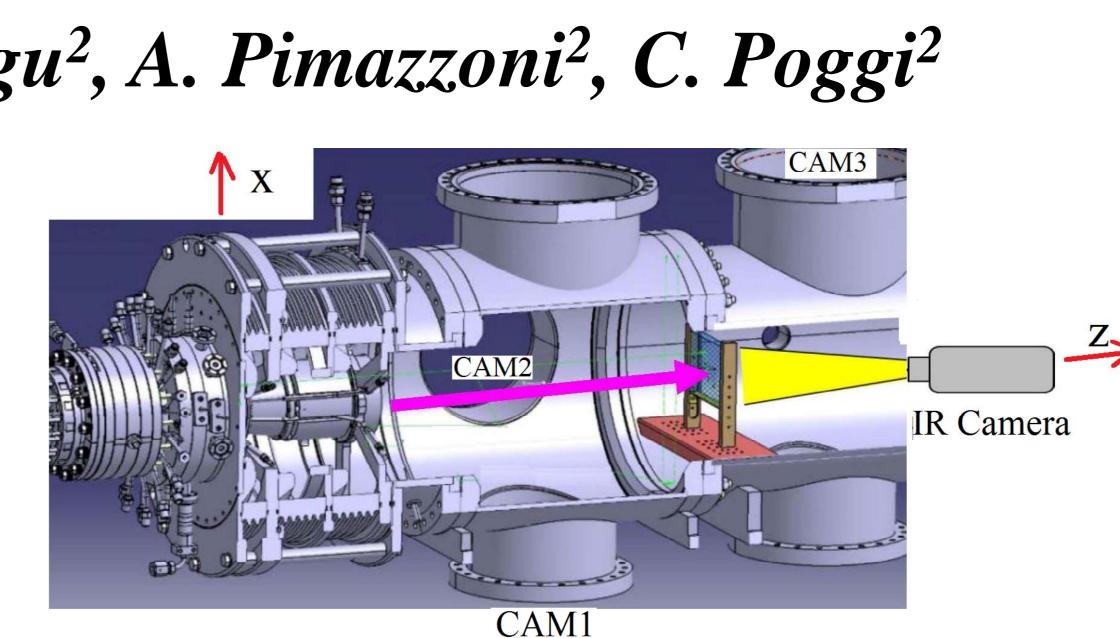


Figure 1. Overall 3D cut view, showing part of NIO1 accelerating electrodes; note CAM1, CAM2 and CAM3 placement; CFC tile recently moved after CAM3 position

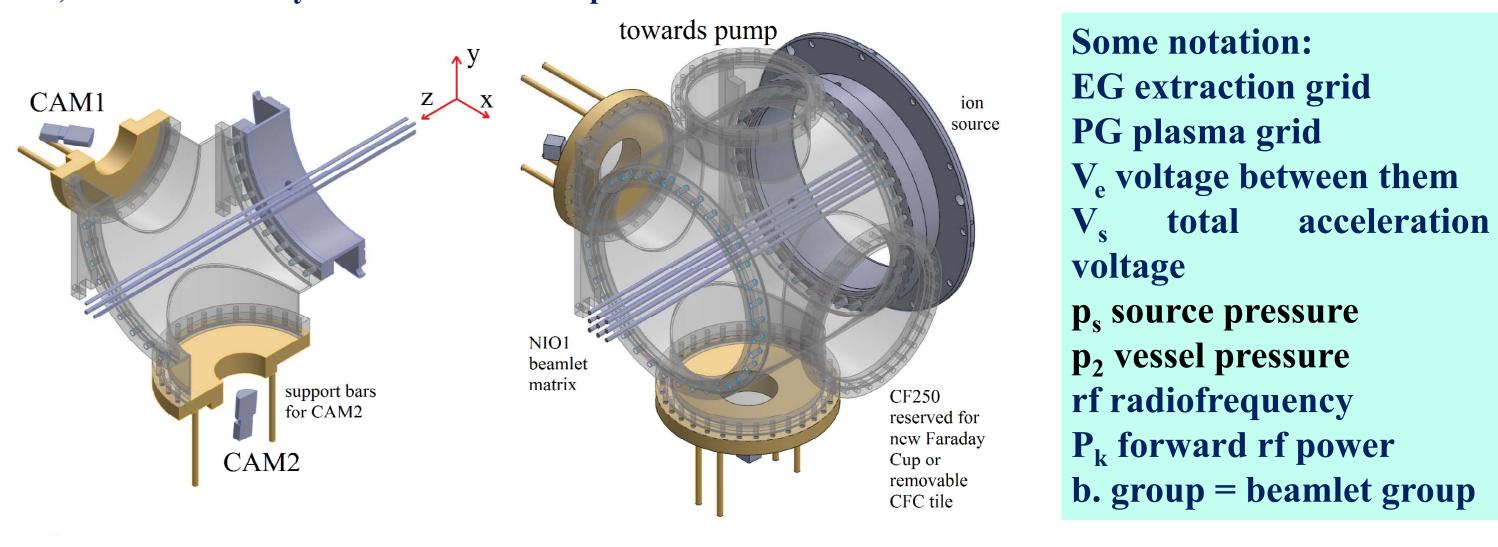
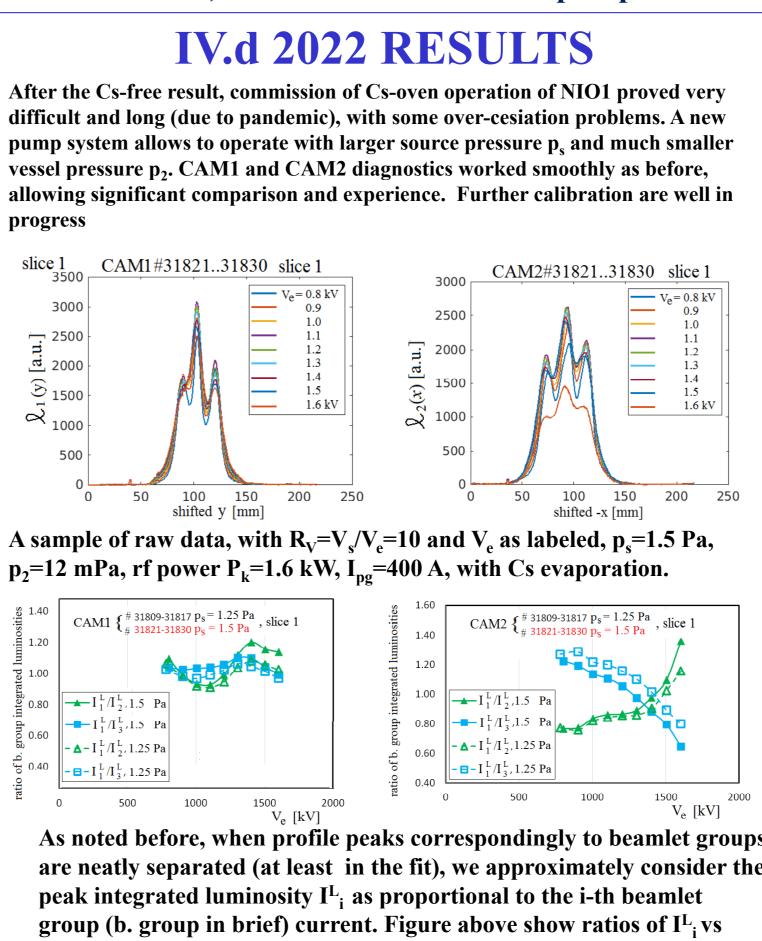
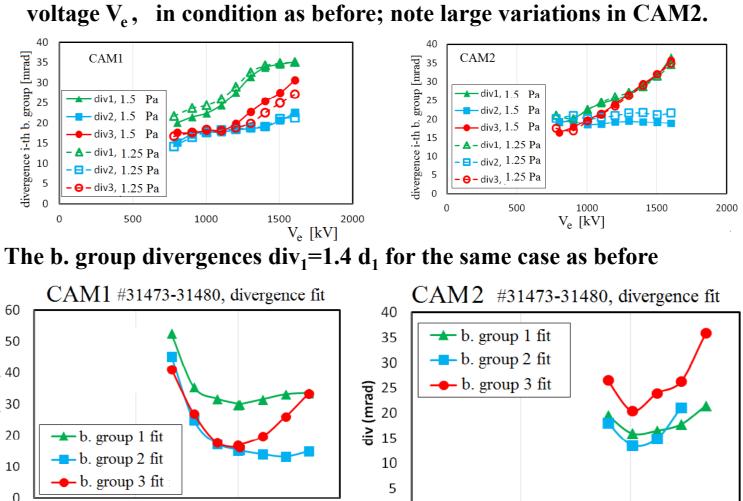


Figure 2. 3D geometry of camera setup: (a) section, with z the beam axis; note CAM1 larger tilting (b) overall view, note CAM2 looks to the pump





fit 4g + poly1



10 V_{s}/V_{e} 15

The b. group divergences, now as a function of $R_v = V_s/V_a$. This is most important, for beam optics. Note the typical smile shape, near the minimum at $R_v \approx 10$

¹⁰ V_s / V_e

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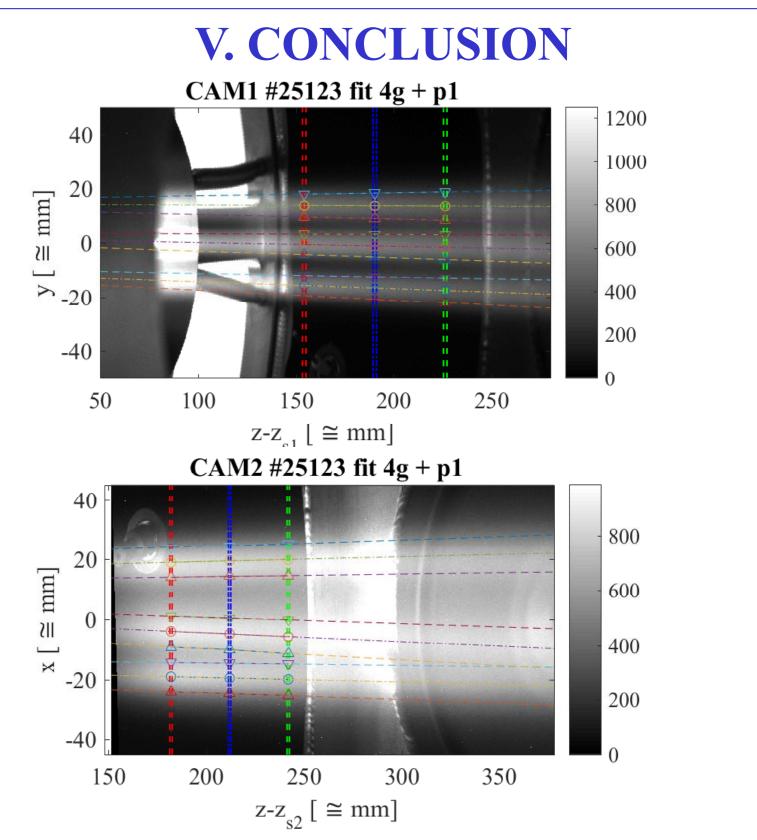


Figure 8. Reconstruction of beamlet borders: (a) CAM1 view (b) CAM2 view; note that extrapolations of beamlet borders 1 and 2 do intersect in front of the pump, as also directly evident from image

The data of NIO1 CAM1 and CAM2 allows to test several fit formula, that were implemented with some attention to practically avoid both over-constrained fit and ill-conditioned fits. While the measurement of current may have perspective of advantages with '3g' fit or 'refit', the border reconstruction clearly show the usefulness of the '4g+1p' fit, perhaps as an additional tools. Beamlet displacement and deviation can be better observed from the border reconstruction, typically based on '4g+1p' fit. In some case, exploration of border reconstruction 'predicts' beamlet groups crossing, directly observed on some CAM2 images. This is consistent with some theoretical approach[5], even if more analysis is surely worthwhile. The crossing of beamlet groups is yet not observed on CAM1, while the data from the new CAM3 being commissioned may allow much more precise observation, at least of deflection in zy plane.

References

- [1] M. A. Lieberman and A. J. Lichtenberg, Principles of Plasma Discharges and Material Processing, John Wiley, New York, 1994
- [2] Taccogna F, Minelli P and Longo S, (2013), Plasma Sources Sci. Technol. 22 045019
- [3] Veltri P, Cavenago M and Serianni G, (2014) Rev. Sci. Instrum. 85, 02A711 http://dx.doi.org/10.1063/1.4826075
- [4] M. Cavenago, M. Barbisan, R. Delogu, et al., Beam and installation improvements of the NIO1 ion source, Rev. Sci. Instrum, 91, (2020) 013316
- [5] M. Cavenago and P. Veltri, Plasma Sources Sci. Technol., 23 (2014) 065024. [6] M. Cavenago, G. Serianni, C. Baltador, et al., The NIO1 negative ion source: Investigation and
- operation experience, AIP Conf. Proc. 2052, 040013 (2018)
- [7] M. Ugoletti, M. Agostini, M. Barbisan et al., Visible cameras as a non-invasive diagnostic to study negative ion beam properties, Rev. Sci. Instrum. 92, 043302 (2021).